

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10520031	MARTON ET AL.
Examiner	Art Unit	
Young J Kim	1637	

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
Patent Databases (USPT, USPPGP, EPO, JPO, DERWENT, IBM-TDB)	8/26/2008	/YJK/
see enclosed for text-search strategy	8/26/2008	/YJK/

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

	/Y. J. K/ Primary Examiner, Art Unit 1637
--	--